



D10 Application Training

D10 Training Outline

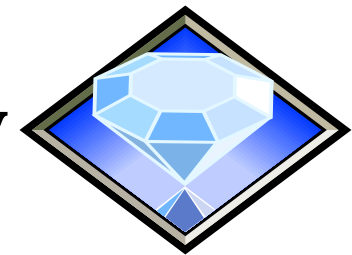
- Day1:
 - Platform Overview
 - Timing And STIL
 - Passive Load
 - Instrument Pin Introduction
 - Program Overview(.job, .res, .sig, user_main, user_load, API etc)
- Day2:
 - Lab: ITE Environment
 - Lab: Run the Program
 - Lab: Run the Tool(shmoo, margin, pattern tool etc)
 - Frequency Measurement
 - To Use the DIBU

D10 Training Outline

- Day3:
 - Lab: Write your own test program (74193)
 - Binning
 - OIC



D-10 Technical Overview

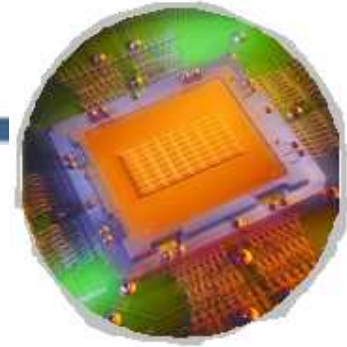


Use of Existing Technology

- Use of industry standards
 - STIL (Standard Tester Interface Language) Syntax
 - Star Fabric cPCI bridge to backplane
 - cPCI data bus interface
 - Third-party cPCI and PXI instruments
 - Third-party software tools
- Use of existing Credence technology
 - Omni ASIC for the DPIN96
 - Octet analog instruments for DMSI
 - Program Developer for program generation
 - Test Developer for pattern generation
 - Debug tools adapted from multiple platforms
 - VI technology from SZ
 - RF and Power Management technology from ASL

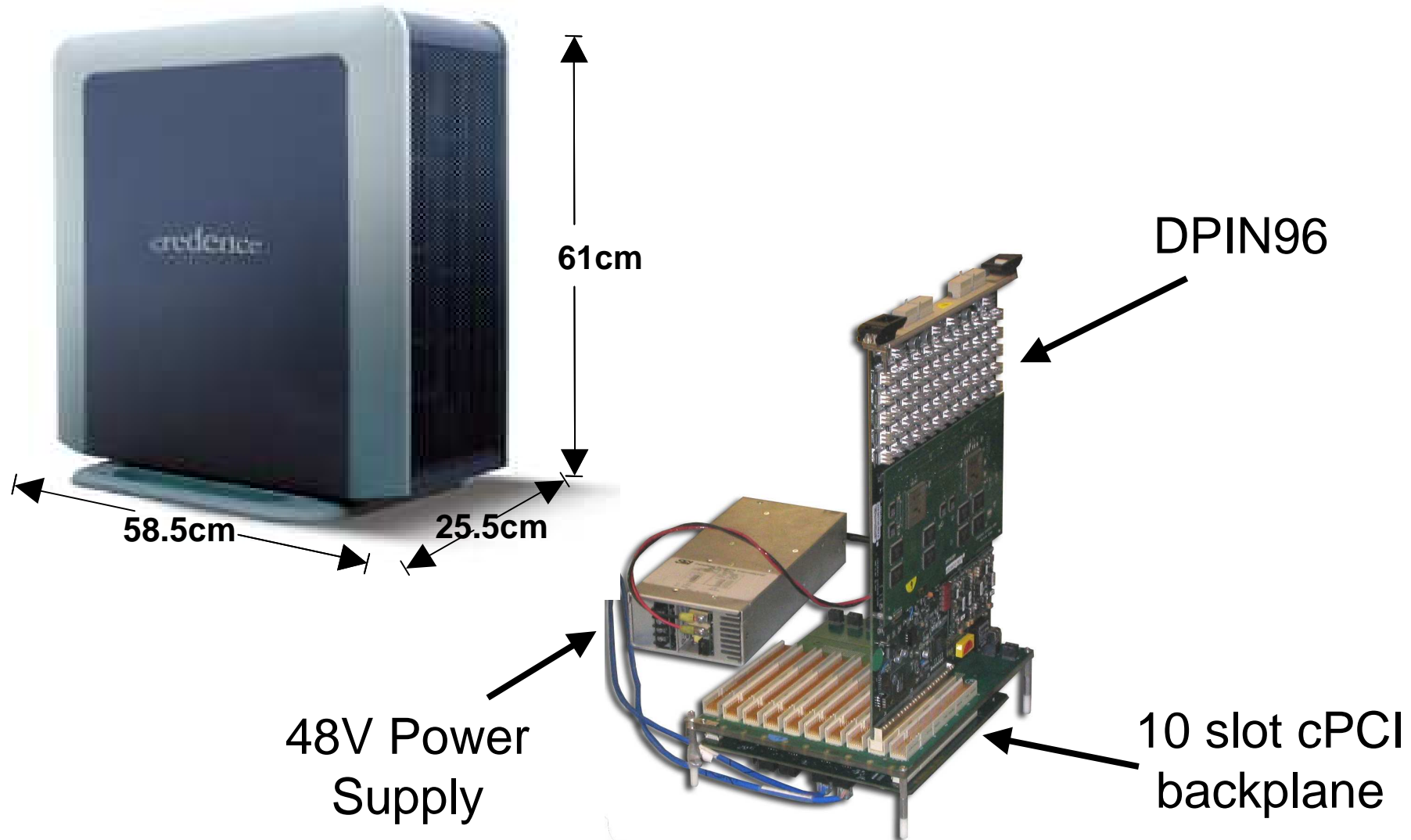


Architected for Performance



- Designed for multi-site
 - Sites management implemented in hardware for maximum throughput and minimum overhead
 - Multi-site analog and DC instruments
 - D-10 software designed for multi-site
- Designed for Maximum throughput
 - 250 Mbyte/s Star Fabric bridge for fast data transfers and pattern loads
 - FPGA based firmware algorithms implemented to accelerate throughput

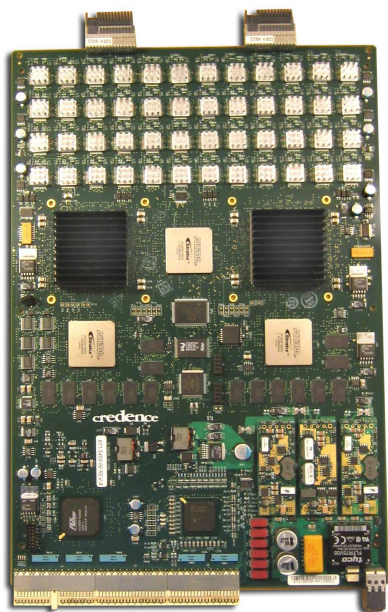
Sapphire D-10



D-10 Digital / MS Instruments

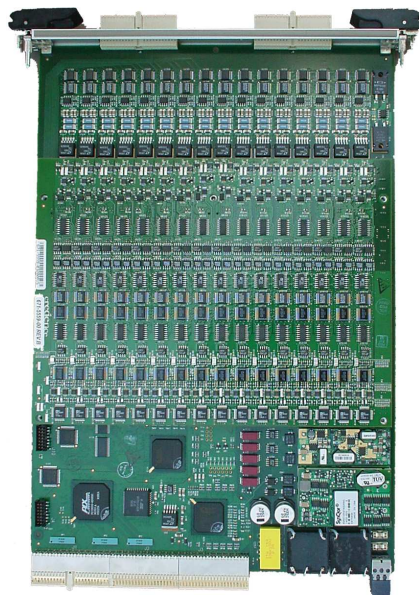
Digital Pins

- 96 pins, 200Mbps
- 16M parallel vector memory, reconfigurable scan



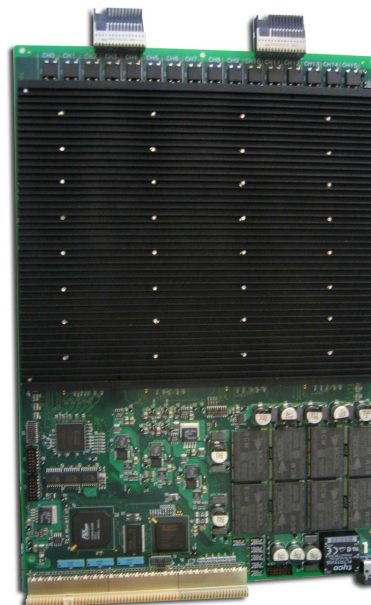
Device Power

- 16 supplies
- 0 to +6V, 2A
- Gangable to 16A



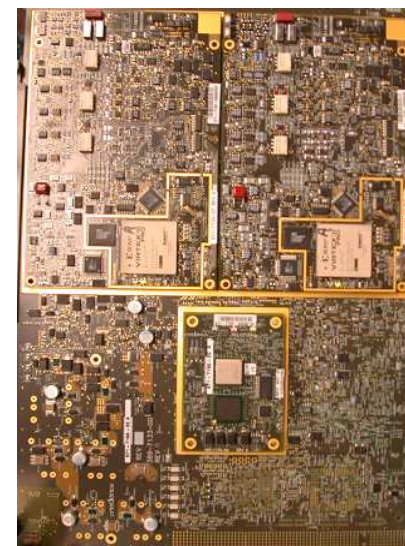
VI Sources

- 16 pins, 4 quadrant
- 20V, 300ma
- 60V, 100ma

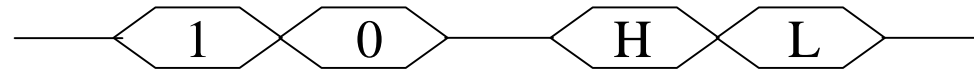


Quad M/S Instruments

- Audio/Video AWG
- Audio/Video Digitizer

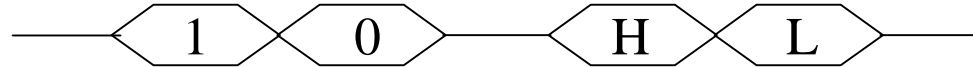


DPIN96 Digital Pincard



Feature	Diamond DPIN96
Channels per card	96
Max Drv or Cmp	200Mbps
Full Format I/O	200 Mbps
EPA	$\pm 500\text{ps}$
Edge Resolution	19.5ps
Rise Time	1.2ns @ 3V
Drv Min Pulse	4ns @ 3V
Drv / Cmp Range	-1V to 6V
Drv Super Voltage	12V
Per Pin PMU	-2V to 12V, $\pm 25\text{mA}$

DPIN96 Digital / Omni asic

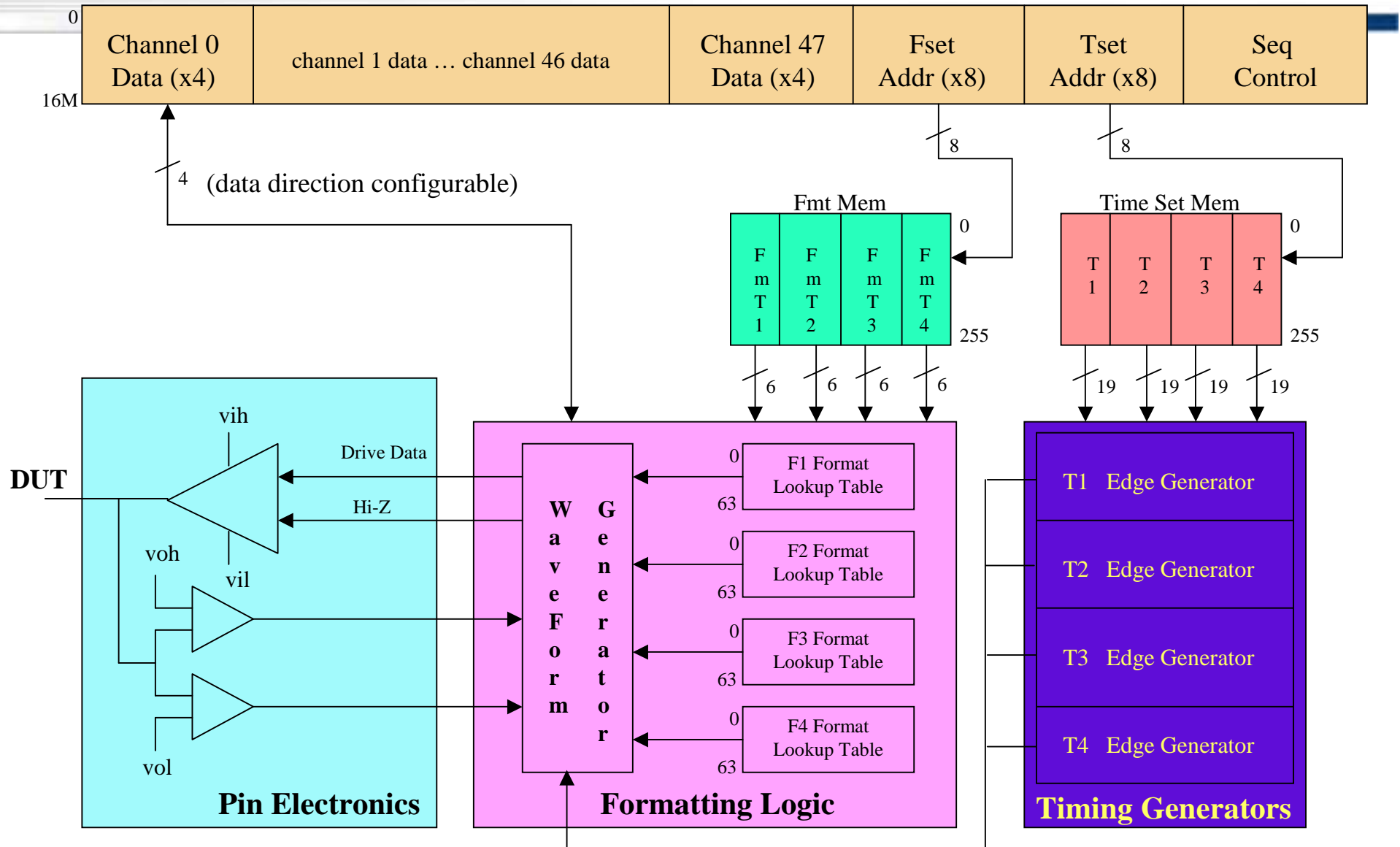


Feature	Diamond DPIN96
Instruction Rate	100 MHz
Edges per pin	4
Data bits per pin	4
Time Sets:	256 period (global)
t1 t2 t3 t4	256 edge per pin (global)
f1 f2 f3 f4	256 format per pin (global)
Memory Depth	16 Meg
Scan	Yes/Reconfigurable
Fail Capture	64 / 16 Meg



DPIN96 Timing

Vector Data Flow

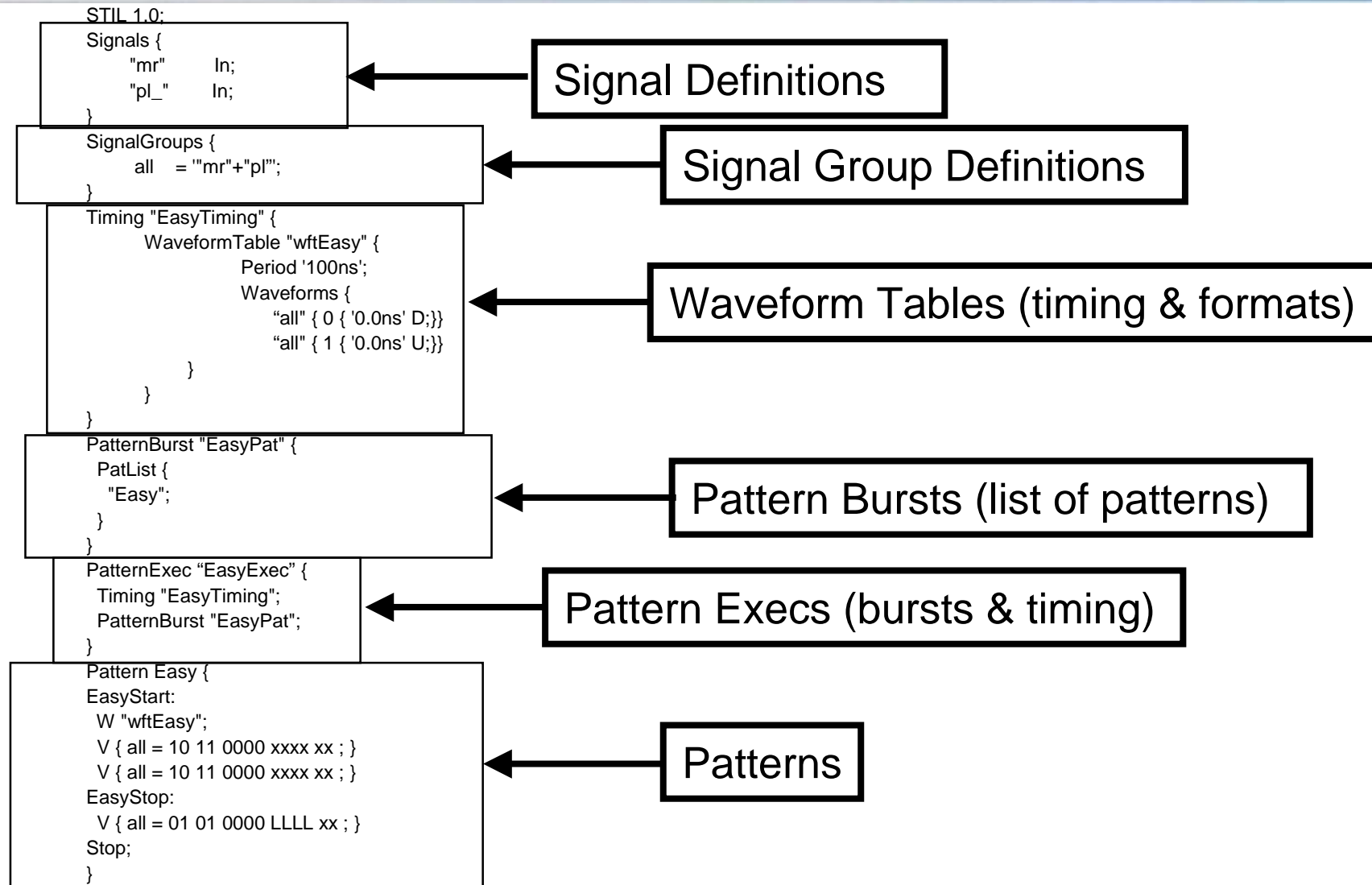


(1) Omni path shown / (1) channel data path shown



Timing Examples in STIL

The STIL File



Signals and Signal List Definitions

```
Signals {  
    "mr"      In;  
    "pl_"     In;  
}
```

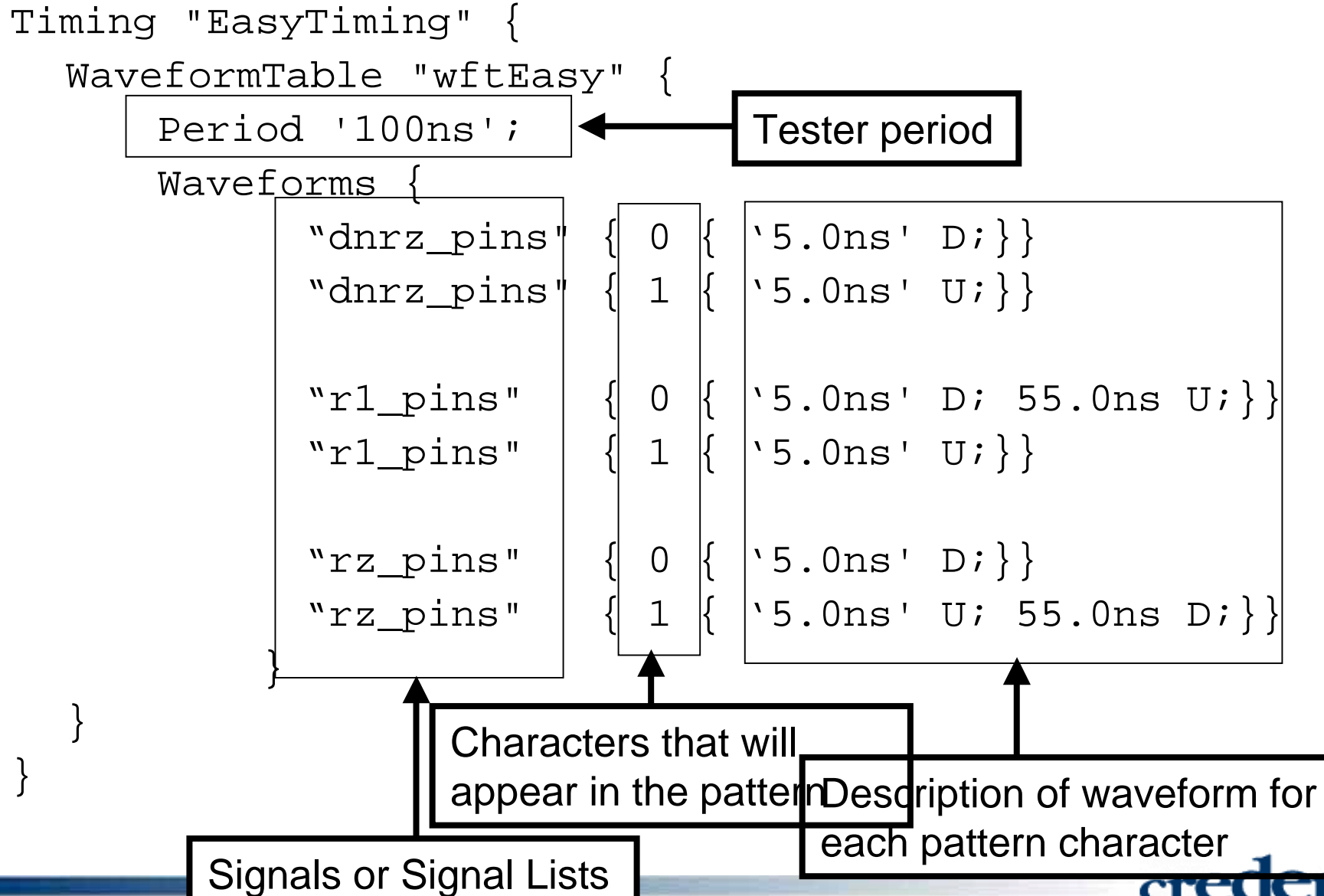
- Valid types are In, Out, InOut, Supply and Pseudo
- Scan pins also declared here

```
SignalGroups {  
    all = "mr"+"pl";  
}
```

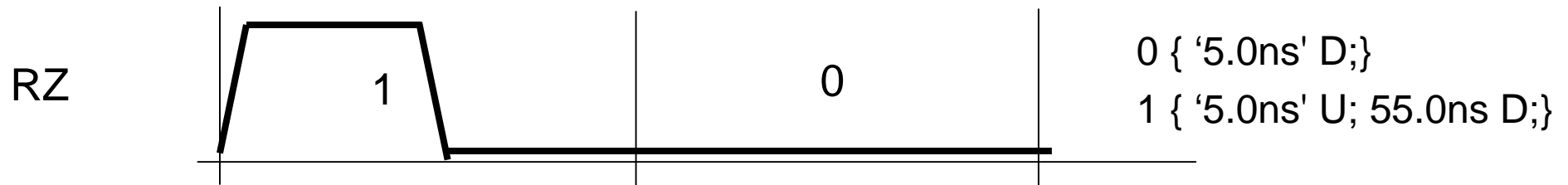
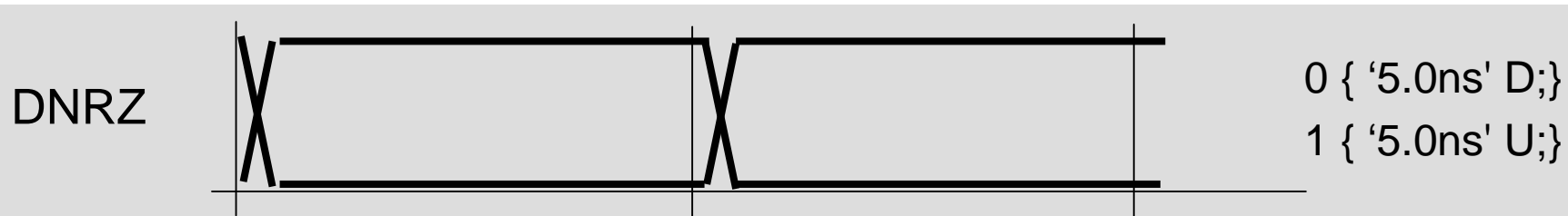
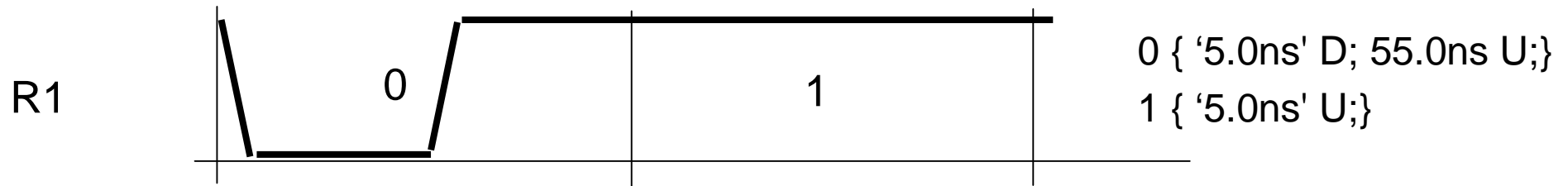
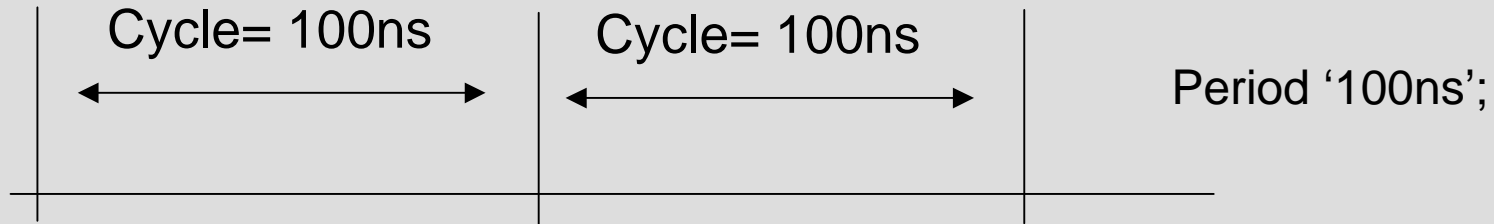
- Expressions may contain signal names or signal group names
- “Quotes” around names are optional

See the Programmer's Reference Manual or the STIL IEEE spec for more information on STIL file syntax

Waveform Table Examples



Waveforms for Timing Examples



Four Edges Per Cycle

Edges	Edge 0	Edge 1	Edge 2	Edge 3
Events	X, Z	D, U, U1, N	D, U, U1, T, V,	H, L, h, l
Allocated			t, v	

- The D-10 STIL compiler imposes some rules on the edge formats
- If not specified by defining 'Z' for a given signal, then the inhibit edge will default to 0ns
- Pattern states are:

Z= inhibit driver

X= mask

D= drive down

U= drive up

T,t= compare for tristate

V,v= compare for valid

H,h= compare for high

L,l= compare for low

Waveform Table Examples

```
Timing "EasyTiming" {  
  WaveformTable "wftEasy" {  
    Period '100ns';  
    Waveforms {  
      "dnrz_pins" { 0 { '5.0ns' D; } }  
      "dnrz_pins" { 1 { '5.0ns' U; } }  
  
      "r1_pins" { 0 { '5.0ns' D; 55.0ns U; } }  
      "r1_pins" { 1 { '5.0ns' U; } }  
  
      "outputs" { H { '5.0ns' H; } }  
      "outputs" { L { '5.0ns' L; } }  
      "outputs" { T { '5.0ns' T; } }  
    }  
  }  
}
```

Edge0

Edge1

Edge2

Edge3

The STIL File

```
PatternBurst "EasyPat" {  
  PatList {  
    "Easy";  
  }  
}
```

Pattern Bursts (list of patterns)

```
PatternExec "EasyExec" {  
  Timing "EasyTiming";  
  PatternBurst "EasyPat";  
}
```

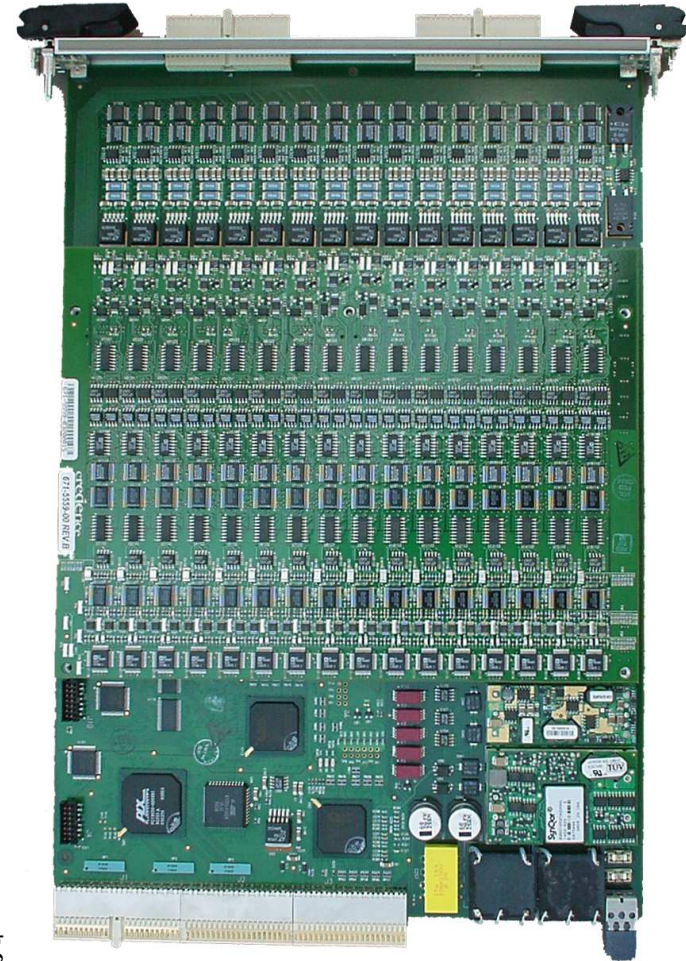
Pattern Execs (bursts & timing)

```
Pattern Easy {  
  EasyStart:  
    W "wftEasy";  
    V { all = 10; }  
    V { all = 10 ; }  
  EasyStop:  
    V { all = 01 ; }  
  Stop;  
}
```

Patterns

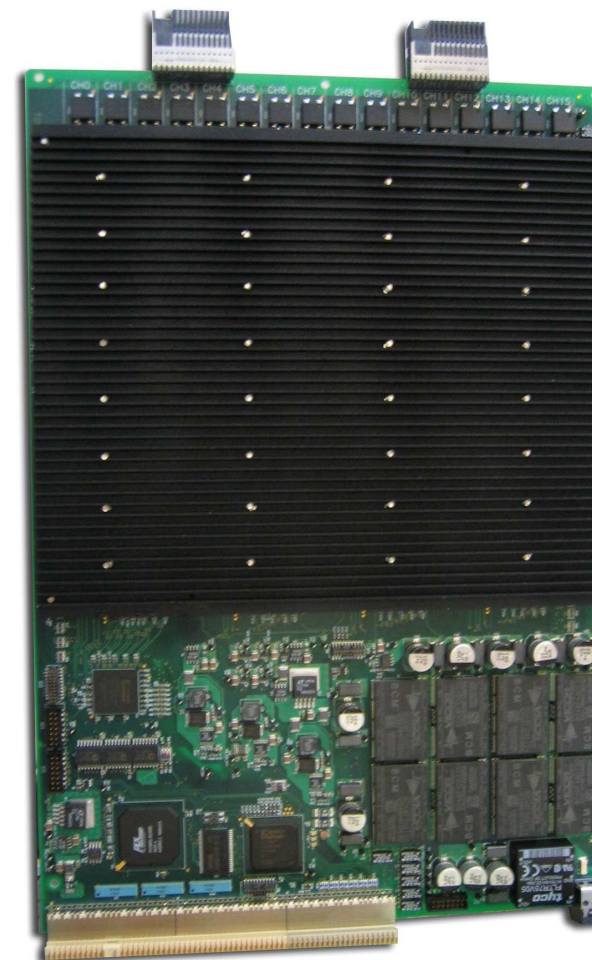
DPS16 Device Power Supply

- 16 source / measure channels
- Vforce:
 - 0 – 6 V positive only
 - 0.1% accuracy
 - 13 bit resolution
 - 2 amps per channel
 - 8 channels ganged to 16 amps
- Iranges:
 - 2A / 200mA / 2mA / 200uA
 - 0.2% accuracy
 - 16 bit resolution
- Current clamps:
 - 2% accuracy
 - 2A range
- Programmable / triggered 4k location cmd stack
- 64k location sample memory w/ on board averaging

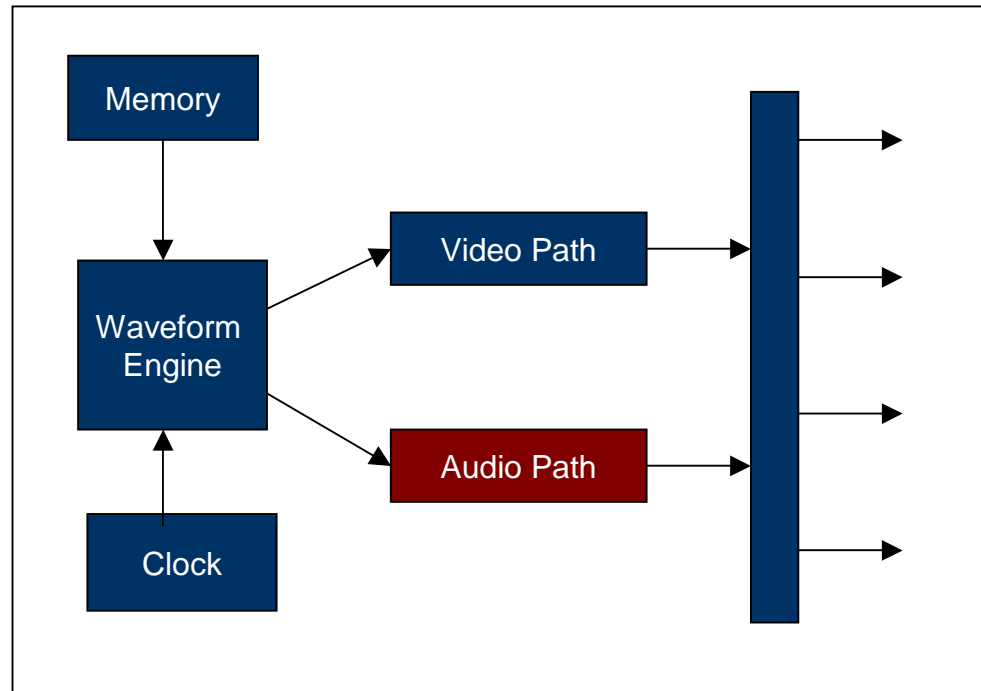


VIS16 – 4 Quadrant VI Source

- Sixteen VI source / measure channels
- Four quadrant operation in two configurations:
 - $\pm 20\text{V}$ @ $\pm 300\text{mA}$
 - $\pm 60\text{V}$ @ $\pm 100\text{mA}$
- 20V / 60V configuration programmable per channel
- Single ended voltage ranges:
 - $\pm 2\text{V}$ / $\pm 6\text{V}$ / $\pm 20\text{V}$ / $\pm 60\text{V}$
- Differential voltage meas ranges (between 2 channels):
 - $\pm 20\text{mV}$ / $\pm 200\text{mV}$ / $\pm 2\text{V}$ / $\pm 10\text{V}$
- Current ranges:
 - $\pm 300\text{nA}$ / $\pm 3\text{uA}$ / $\pm 300\text{uA}$ / $\pm 30\text{mA}$ / $\pm 300\text{mA}$
- $\pm .03\%$ FSR accuracy / $\pm .01\%$ FSR repeatability
- Programmable compensation for speed and stability
- Programmable low pass filter for measured functions
- Analog modulation up to 20kHz for PSRR tests
- Internal and external triggers for measurement sampling into 1024 location capture memory
- 50uF max capacitive load



D-10 AWG

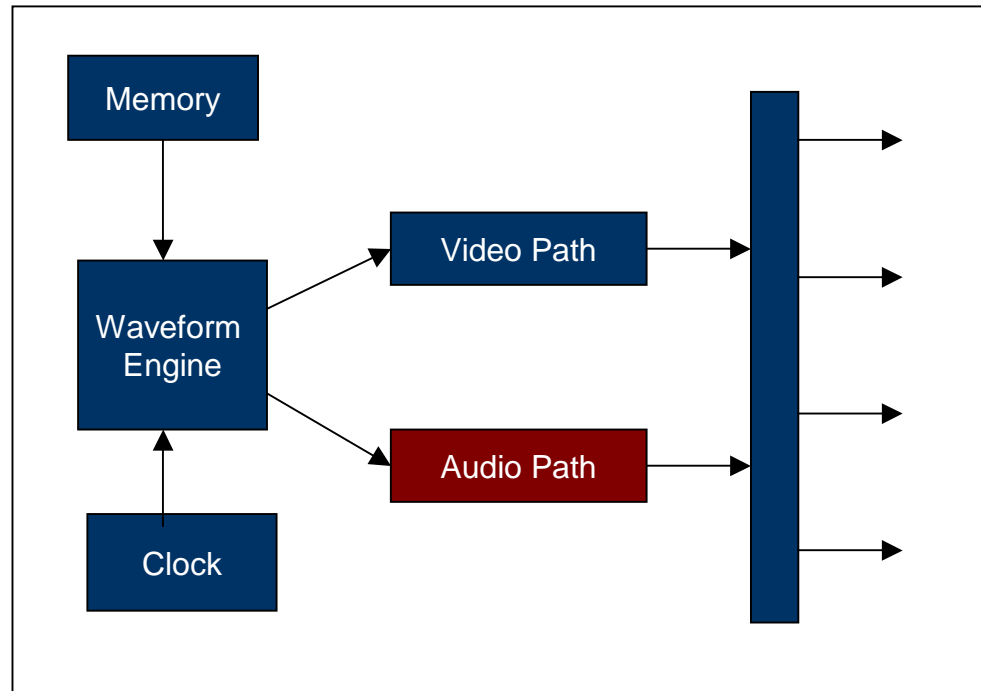


AWG

Multi-Site, Multi-Band AWG

- Channels can be used single-ended or differentially
- 4 channels share the same waveform memory and the same clocking
- Offset voltage is independently adjustable
- A high-frequency video path and a high-resolution audio path are available for each channel

D-10 AWG



AWG

Multi-Site AWG

- Sampling rate: 300Msps
- Audio w/1KHz BPF:
 - THD 120dB
 - SNR 105dB
- Video:
 - SNR 70dB
 - SFDR@20MHz 70dB

Instrument Clock

- Jitter < 3ps rms

Sapphire D-10 AWG

Feature	Sapphire D-10 AWG
Number of outputs	8 SE or 4 differential
Output impedance	50 Ohms
Output range (open circuit)	8V p-p with $\pm 4V$ common offset and $\pm 400mV$ independent offset
Hardware resolution	20 bits
Maximum sample rate	300 Msps
Waveform memory	1 Megaword
Bandwidth (3dB typical)	LF path: 2MHz, HF path: >100MHz

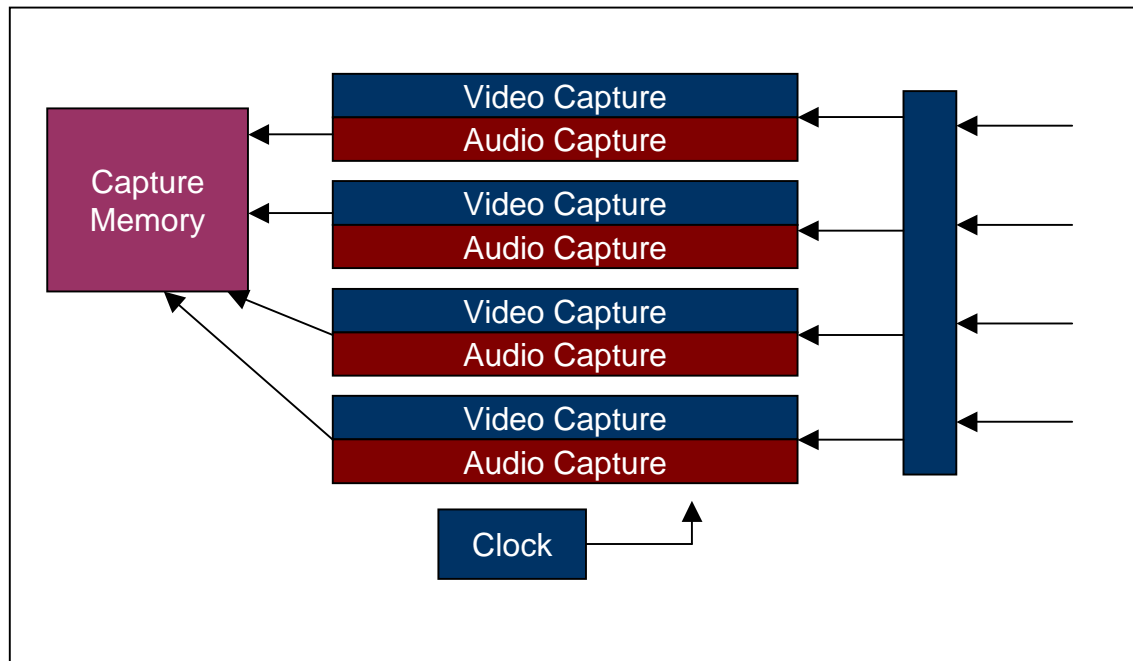
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Sapphire D-10 AWG

Feature	Sapphire D-10 AWG
Jitter (typical)	3 ps rms
HF path filters	2 MHz, 6.3 MHz, 20 MHz, 63 MHz (LP, 5 pole Bessel)
LF path filters	2 kHz, 20 kHz, 200 kHz (LP, 6 pole Bessel) 1 kHz Bandpass (4 th -order Butterworth)
Noise density	8 nV/Hz ^{1/2} (HF path, 1V p-p into 50 Ohms)
SFDR (including harmonics)	85dB at 1MHz 70dB at 20MHz

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D-10 Digitizer

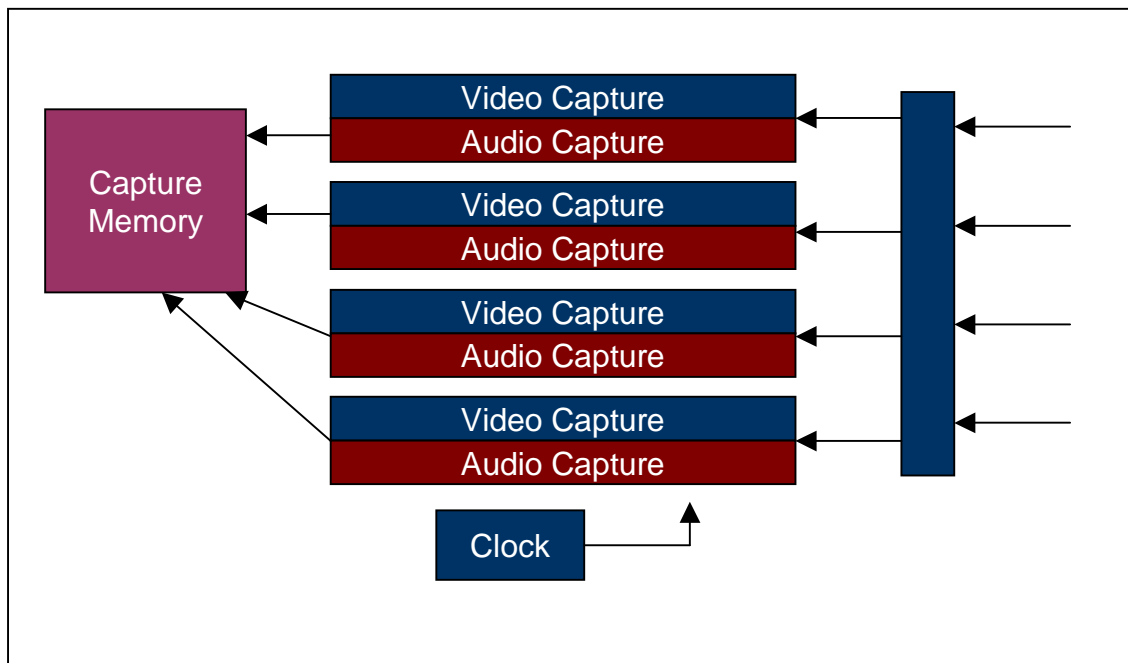


DIG

Multi-Site, Multi-band DIG

- 4 differential input channels share the same clocking and triggering
- A high-frequency video path and a high-resolution audio path are available for each channel

D-10 Digitizer



AVD

- **Multi-Site DIG**

- Sampling rate: 100Msps

- Audio w/1KHz notch:

THD 120dB

SNR 100dB

- Video

SNR 68dB

SFDR@20MHz 70dB

- **Instrument Clock**

- Jitter < 3ps rms

Sapphire D-10 Digitizer

Feature	Sapphire D-10 DIG
Number of channels	4 differential
Input impedance	HF: 50 or 500 Ohms (100 or 1k Ohms differential) to Vterm, programmable from -2V to +6V LF: 10 Mohm or 600 Ohm
Input range	HF: 53mV to 4V (diff p-p, 2.5 dB steps) LF: 106 mV to 8 V (diff p-p, 2.5dB steps)
Maximum sample rate	100 Msps
Waveform memory	0.5 Megaword

Sapphire D-10 Digitizer

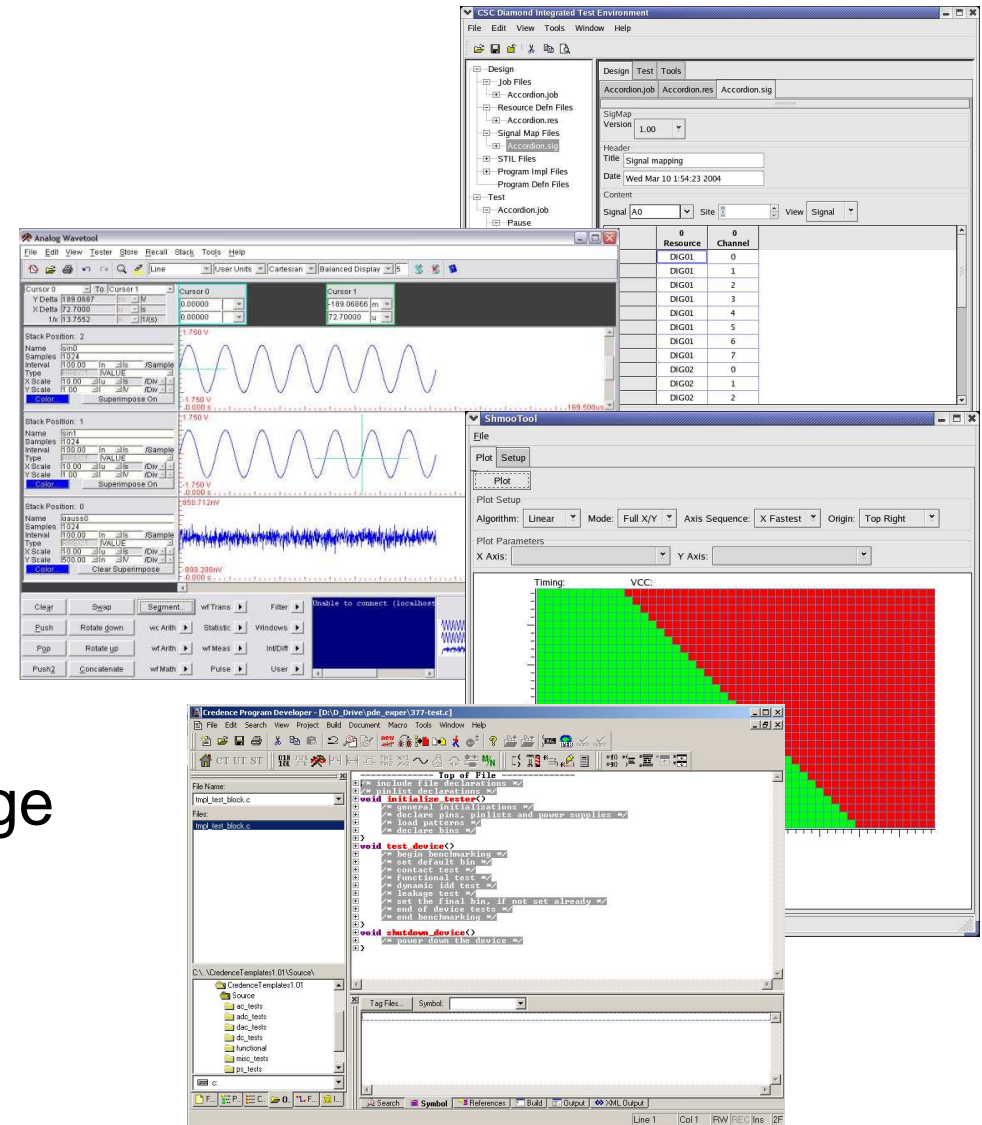
Feature	Sapphire D-10 DIG
ADC resolution	HF: 14 bits, LF: 16 bits
Bandwidth (3 dB typical)	HF: 230 MHz, LF: 4 MHz
Jitter (typical)	3 ps rms
Analog filters	HF: 20 MHz, 63 MHz (low pass, 5 pole Bessel) LF: 63 kHz, 250 kHz (low pass, 4 pole Bessel) 1 kHz (notch with 30 dB gain)
Halfband decimation filters	2x, 4x, 8x, 16x, 32x
Noise density	4 nV/Hz ^{1/2} (53 mV range) 22 nV/Hz ^{1/2} (4.0 V range)
SFDR (including harmonics)	70 dB at 20 MHz (SFDR is nearly flat below 20 MHz)

DIB Utility Board

- Always goes in slot 9 (last slot)
- Is required
- Fixed supplies
- Relay controls
- Communication busses

D-10 Software

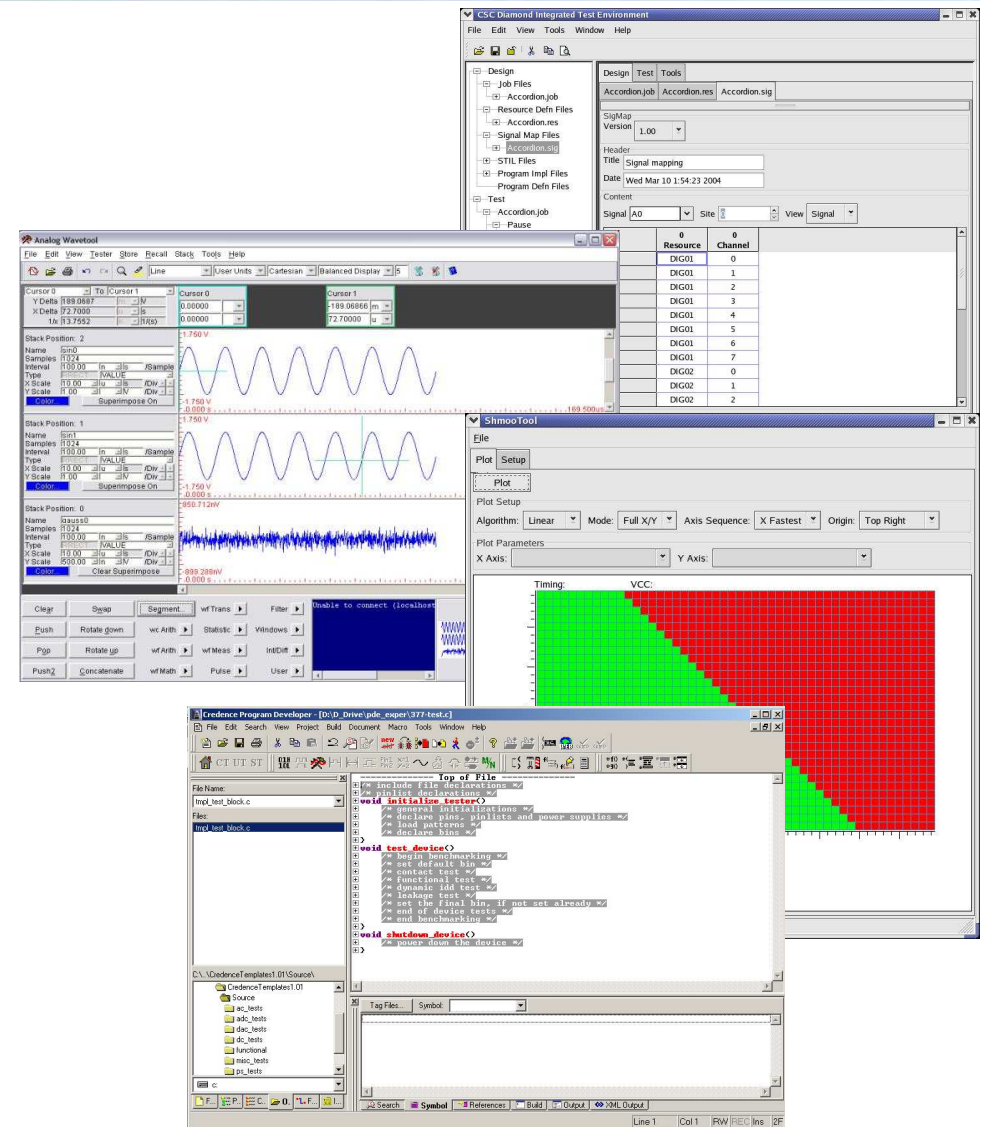
- Simple
- Intuitive
- Open-architecture
- Fast response time
- Fast runtime
- Based on
 - Linux operating system
 - C++ test program language
 - STIL pattern format



D-10 Software

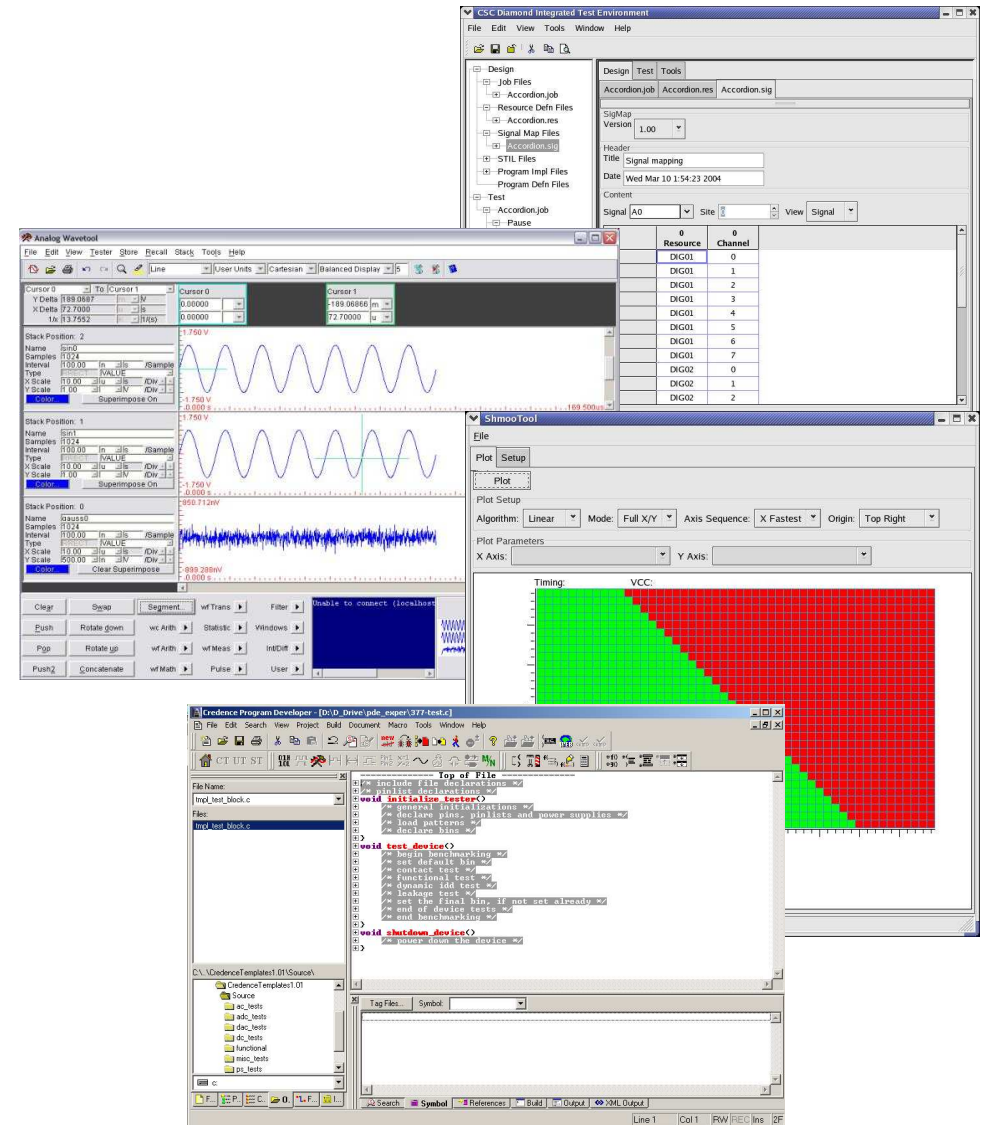
- D-10 is committed to sharing interfaces, tools and formats with other Credence product lines as much as possible

- STIL pattern format
- Analog Wave Tool
- Program Developer
- Test Developer
- Shmoo and Margin tool
- Handler/prober interface
- Galaxy data analysis
- Datalogging formats
- Test templates
- Many more.....



Integrated Test Environment (ITE)

- Project overview
 - Program files
 - Pattern files
 - Tester configuration details
- Operator interface
 - Test setup
 - Run control
 - Datalogging
- Interactive debugging tools
 - Shmoo and Margin tool
 - Pattern tool
 - Analog Wave Tool (AWT)
 - Pin and timing status displays
 - Program Developer tool
 - Interactive debug commands



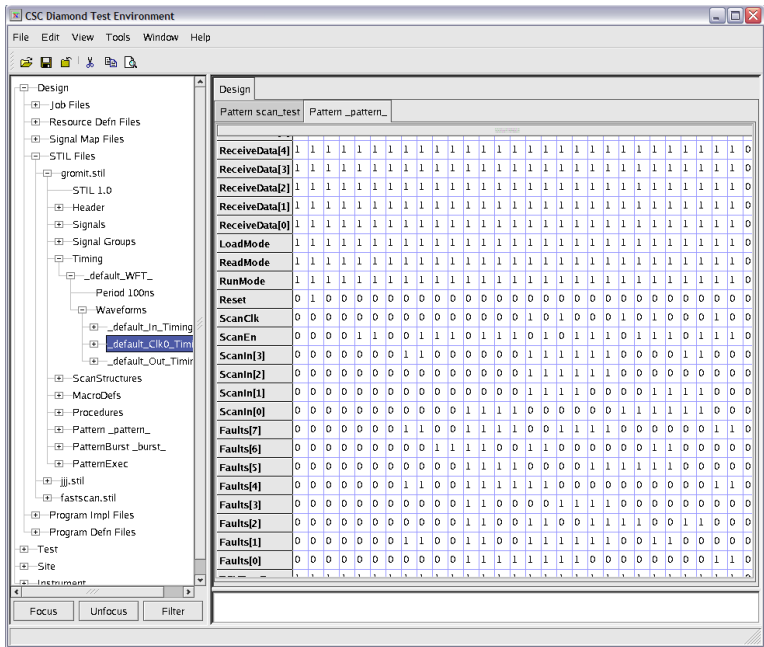
Integrated Test Environment (ITE)

The screenshot shows the CSC Diamond Integrated Test Environment (ITE) window. The interface is divided into several panes:

- Navigation pane:** Located on the left, it displays a hierarchical tree of project files. The 'Test' folder is expanded, showing sub-items like 'Pause', 'Flags', 'API', 'Test', 'Datalog', 'Flags', 'Count 1', 'Override', 'Site', 'Timing', 'Period', 'Levels', and 'Tools'. A yellow callout bubble points to this pane with the text 'Navigation pane'.
- Display and Setup Pane:** The central area, containing tabs for 'Design', 'Test', and 'Tools'. The 'Test' tab is active, showing fields for 'Job Version' (1.0), 'Name' (Test), 'Header' (Title: Test job file for DPIN96, Date: Wed Mar 10 1:54:23 2004), and 'Content' (Resource Definition, Signal Map, Patterns, Loadable Storage Directory, Test Program, Datalog Format). A yellow callout bubble points to this pane with the text 'Display and Setup Pane'.
- Output and Command Pane:** Located at the bottom, it displays a list of commands: 'pause test', 'pause test idd', 'pause test 1234', 'run', 'log dcf', and 'log fail'. A yellow callout bubble points to this pane with the text 'Output and Command Pane'.

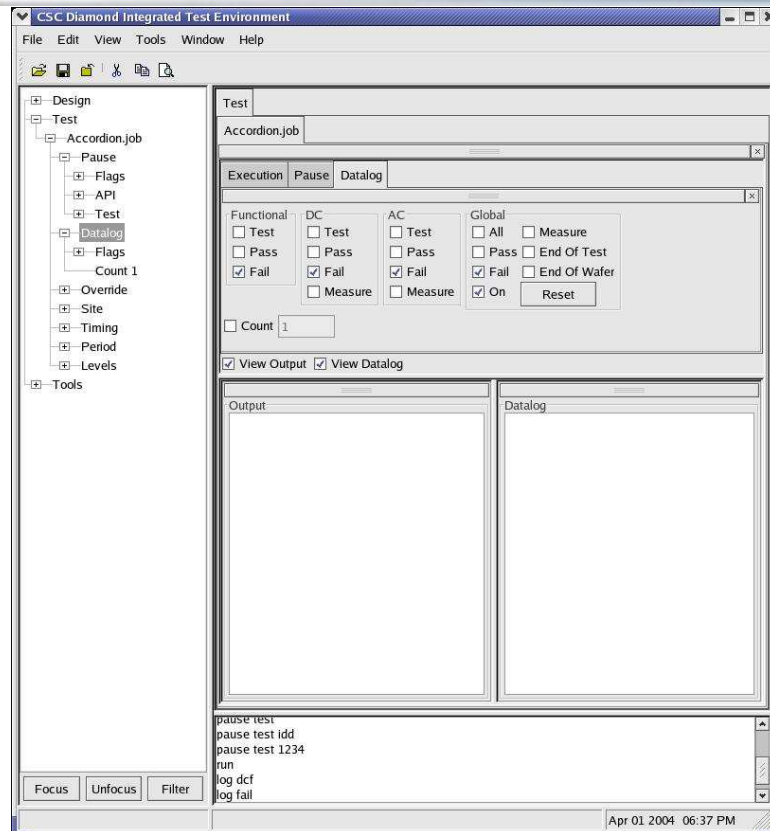
Additional callouts include 'Drag and drop entries from the navigation pane into the display pane to view, modify or launch the respective item' pointing to the central area, and 'Focus', 'Unfocus', and 'Filter' buttons at the bottom left.

STIL in ITE

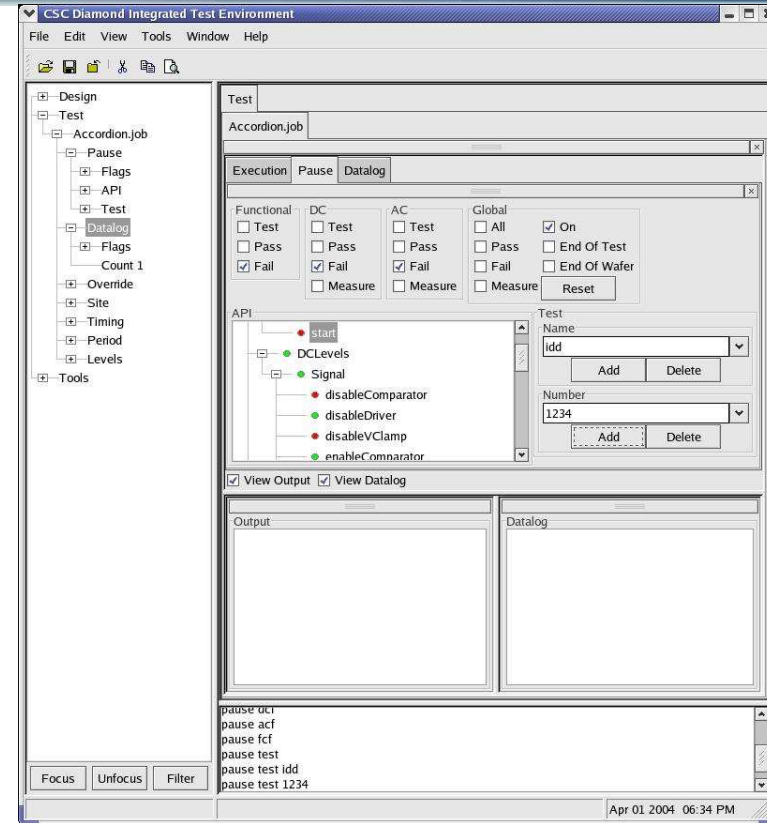


- Pattern, signal, pinlist and timing information is automatically extracted from the STIL file
- ITE provides a graphical display and edit interface for the STIL information

Control Panels



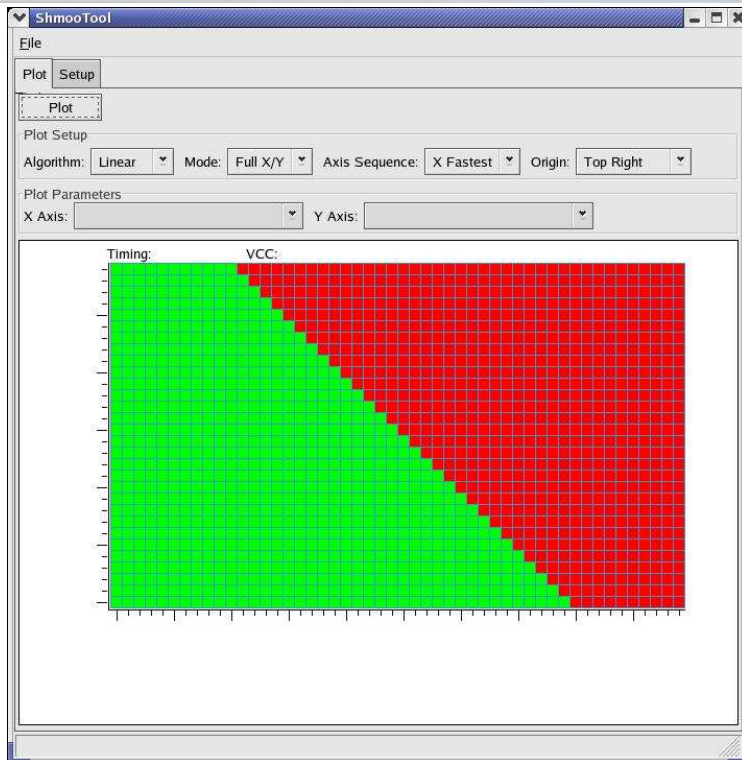
Datalogging



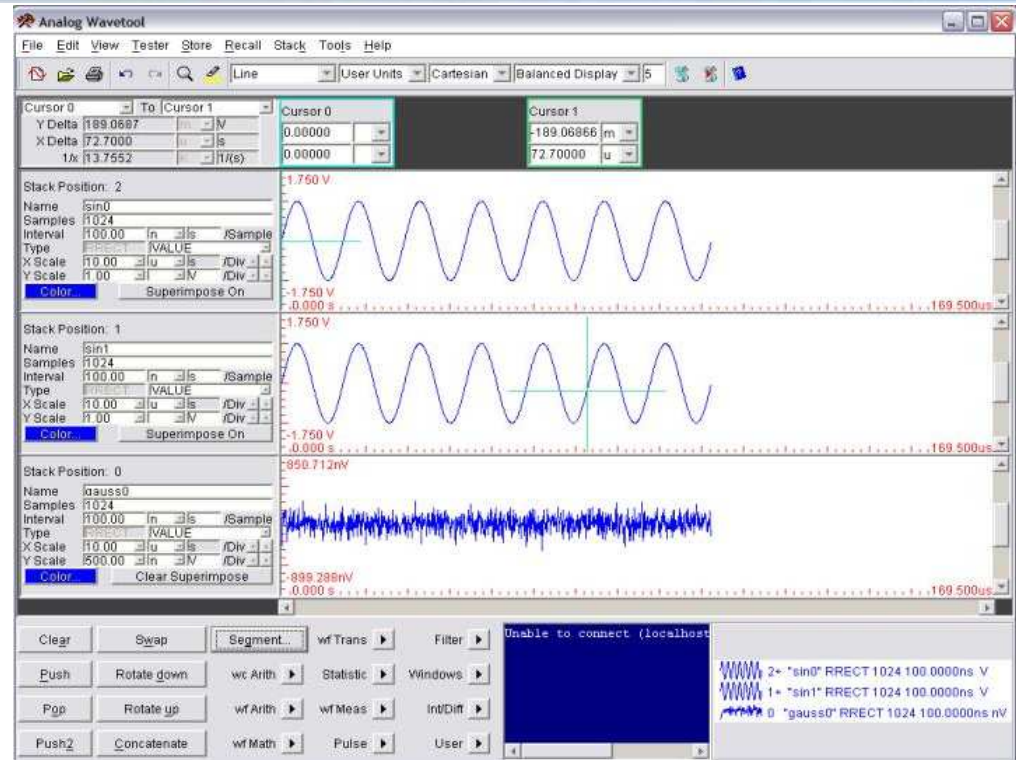
Pausing

- Simple control panels allow the user to control the program and set parameters such as pausing and datalogging flags

Debugging Tools



Shmoo & Margin

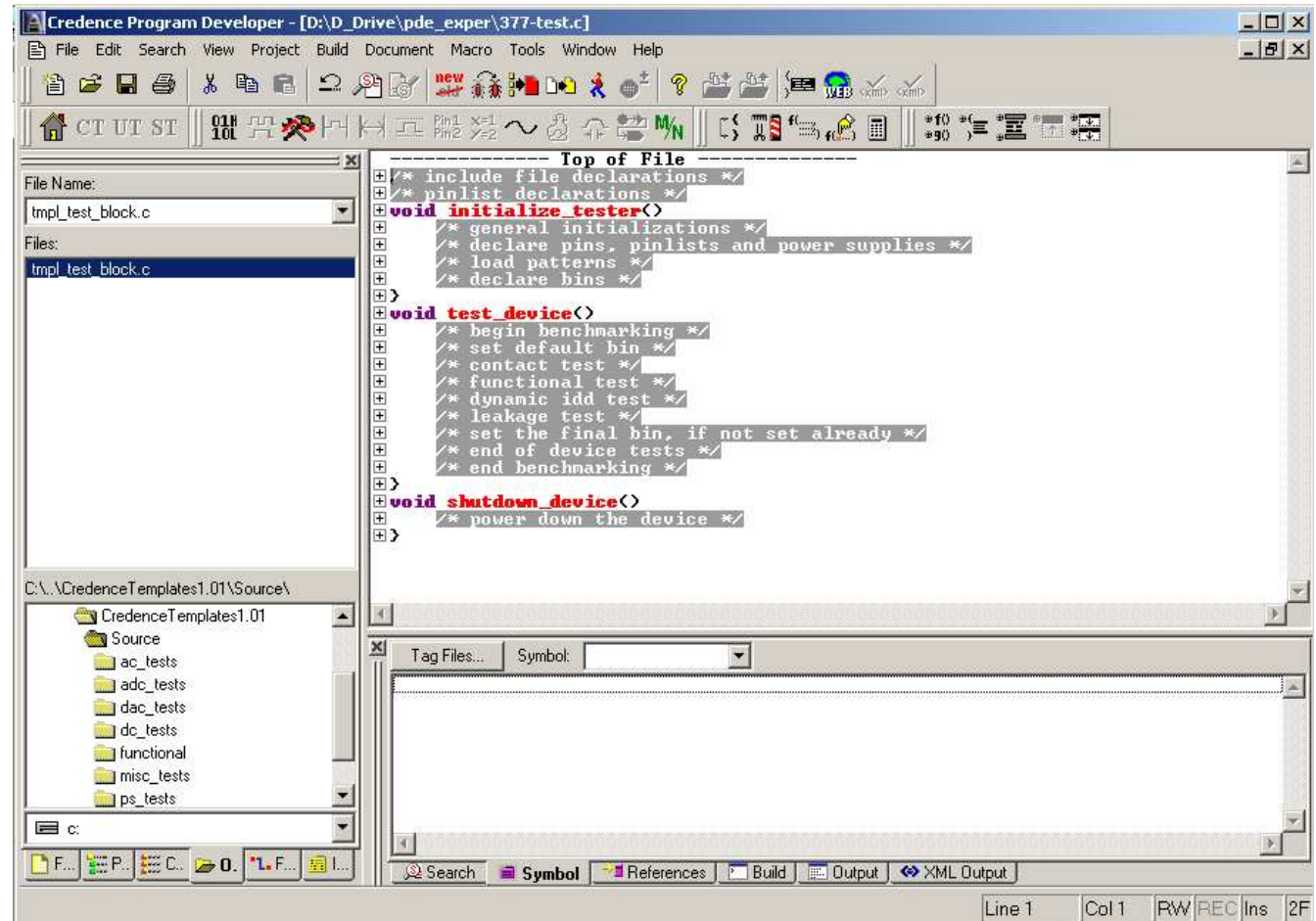


AWT

- Dragging and dropping tools into the display pane will cause them to launch with setups for the current breakpoint
- The display pane can be undocked

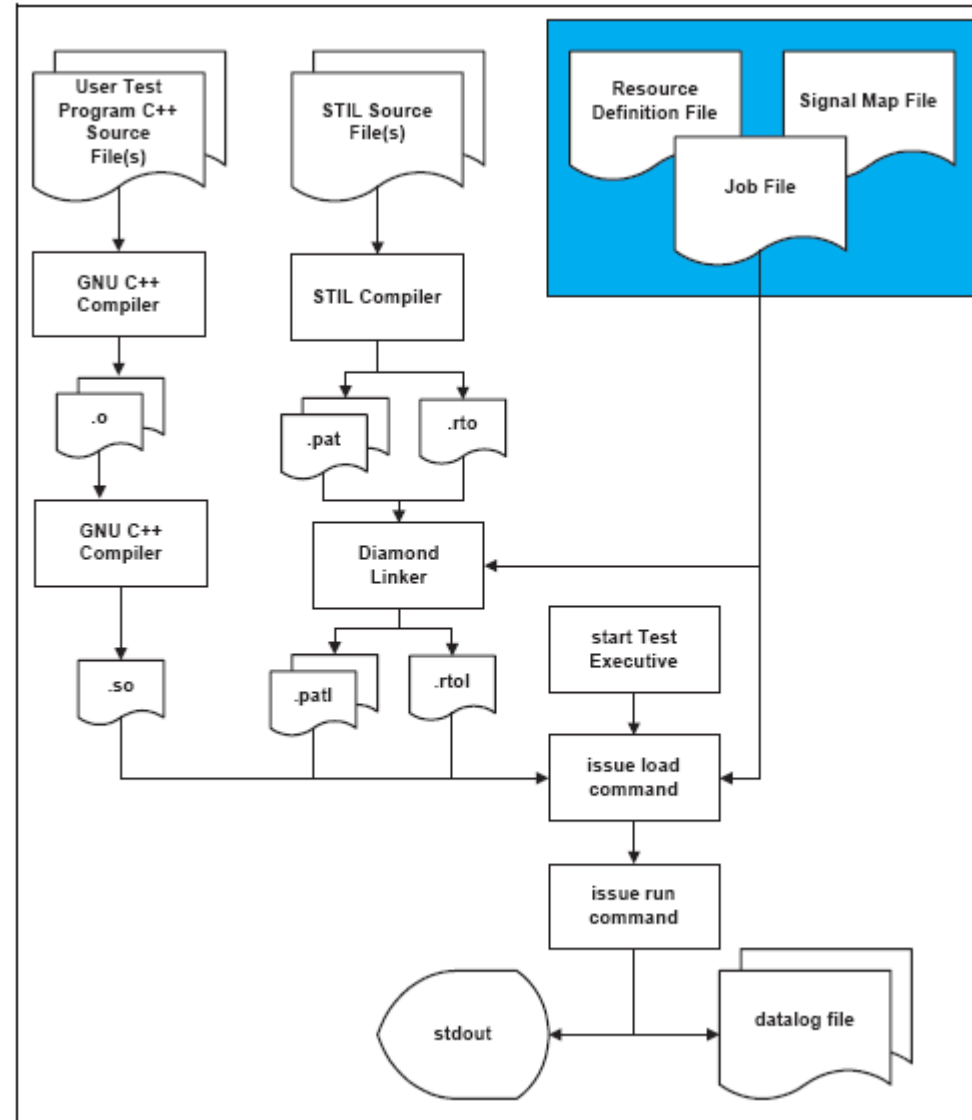
Credence Program Developer

- Available on D-10, Sapphire and Octet
- Powerful program development and debug environment based on the SlickEdit IDE
- Browser is used to navigate directories and organize test templates supplied by Credence or written by users
- Many standard IDE features such as
 - Source code debugger
 - Language-sensitive editor
 - Context-sensitive help
 - Much, much more...



- Program Developer is launched by ITE for test program development and debug

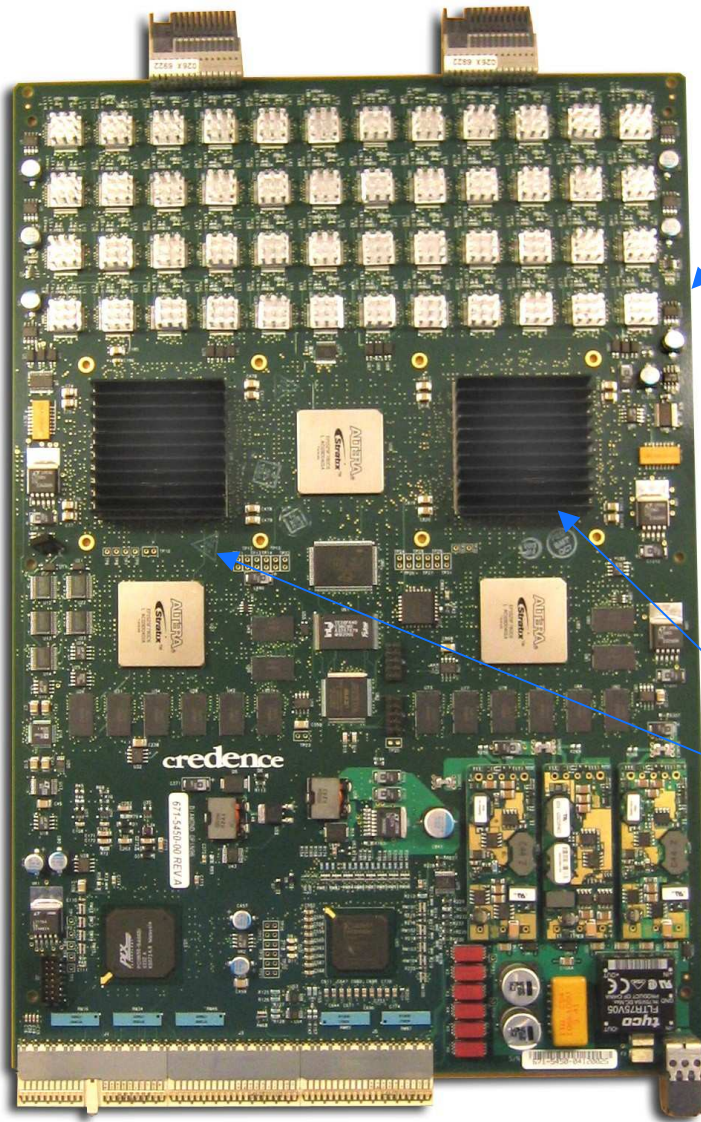
Source Files and Job Creation





Passive Load

DPIN96



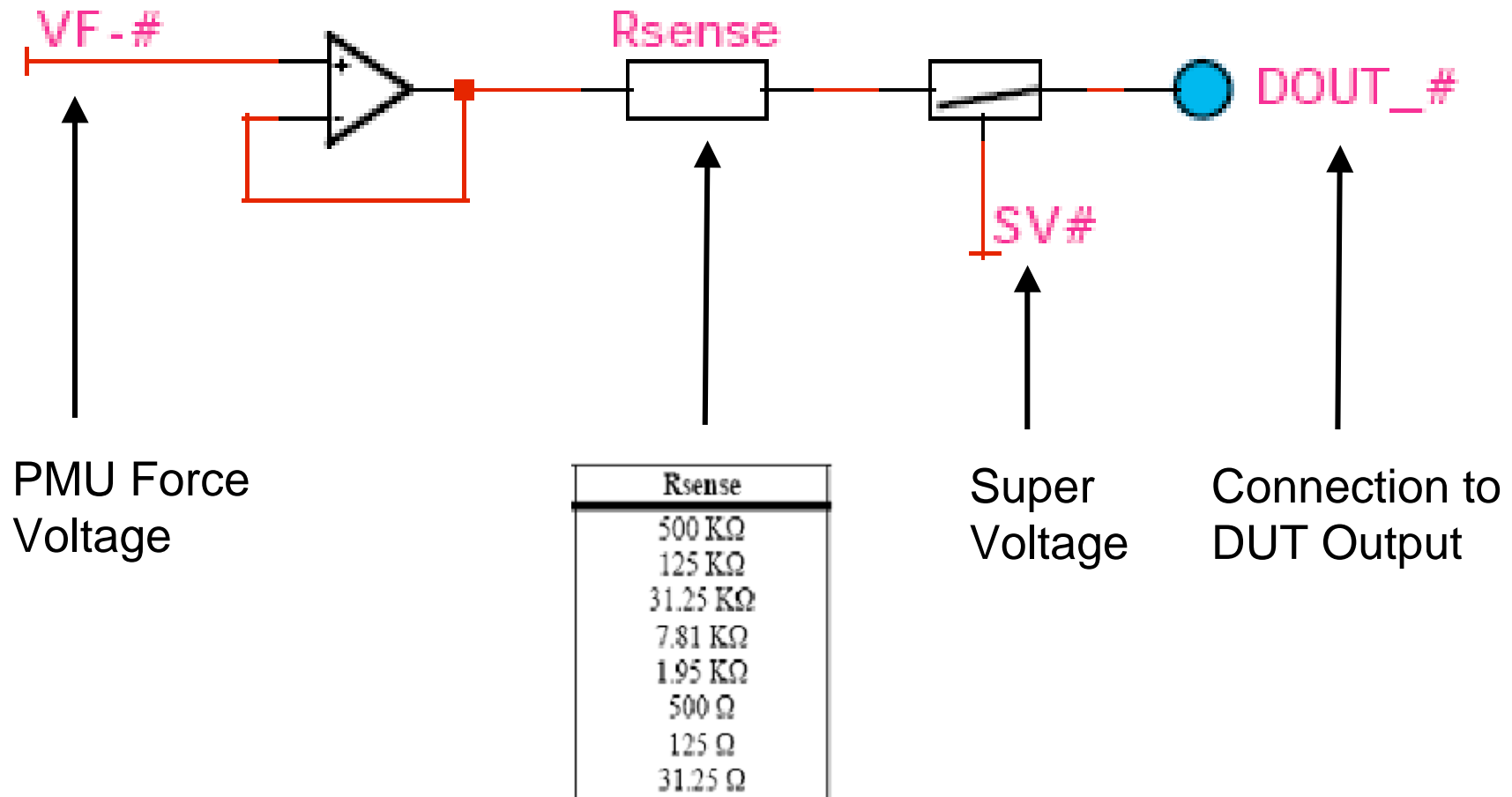
■ PlanetATE driver/comparator/PMU dual channel devices

■ Omni ASICS for timing and APG

DPIN96 Loads

- The DPIN96 has programmable loads per pin
- Loads consist of termination voltage connected through a resistive load
- The value of the resistive load is selected from a list of 8 possible values
- The termination voltage is programmable on a per-pin basis across the range of -1.5V to 12V
- Using the Ohm's Law, the proper values can be chosen to achieve the desired load current
- Both I_{oh} and I_{ol} can be tested by running a 2-pass functional test with the loads set to the respective load currents for each pass

Static Load Circuit



Force and Measure Current Ranges

Current Range	I _{max}	R _{sense}
IR0	2 μ A	500 K Ω
IR1	8 μ A	125 K Ω
IR2	32 μ A	31.25 K Ω
IR3	128 μ A	7.81 K Ω
IR4	512 μ A	1.95 K Ω
IR5	2 mA	500 Ω
IR6	8 mA	125 Ω
IR7	32 mA	31.25 Ω